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PATENT NUMBER

LLS HTILITY Patent Application

O.O. OTTERT I AUGUST PP		 	
MT O.I.P.E.	PATENT DATE		
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APPLICATION NO. 09/986084	CONT/PRIOR F	256 43	SUBCLASS 3	2877.25	EXAMINER YOUNG
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Shuji Nakao Yuki Miyamoto Nachisa Tamada

Focus monitoring method, focus monitoring apparatus, and method of manufacturing semiconductor device

	ISSUING CLASSIFICATION									
ORIGINAL				CROSS REFERENCE(S)						
CL	ASS	SUBCLASS	CLASS SUBCLASS (ONE SUBCLASS PER BLOCK)						257	
			100	1		100		1	20.0	
INTERNATIONAL CLASSIFICATION				100						
					100	1		Commercial		
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TERMINAL		RAWINGS	1	CLAIMS ALLOWED		
L-JDISCLAIMER	Sheets Drwg,	Figs. Drwg.	Print Fig.	Total Claims	Print Claim for O.G.	
The term of this patent , subsequent to (date) has been disclaimed.	(Assissm E	serviner)	(Date)	NOTICE OF ALL	OWANCE MAILED	
The term of this patent shall not extend beyond the expiration date. of U.S Patent. No.				ISS	JE PEE	
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